Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
09/765,516	CHUGG ET AL.
Examiner	Art Unit
Jason M. Perilla	2611

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	316	4/17/2006	JP
	324	4/17/2006	JP
	340	4/17/2006	JP
	341	4/17/2006	JP
	346	4/17/2006	JP
	147	7/17/2006	JP

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
375	324	4/17/2006	JP
	340	4/17/2006	JP
	341	4/17/2006	JP

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
East USPAT/USPGPUB	4/17/2006	JP
Inventor Name Search EAST/EDAN	4/17/2006	JP